

**CERTIFICATE OF CONFORMITY**

Item	Parameter								UOM
	Customer's Requirements				Guaranteed/Actual Values				
Material:	InP				InP				
Conduction type/Dopant:	S-C-N/S				S-C-N/S				
Grade:	Prime				Prime				
Diameter:	76.2±0.3				76.2±0.3				mm
Orientation:	(100)±0.3°				(100)±0.3°				
Orientation Angle:	/				/				
Flat Option:	EJ				EJ				
Primary Flat Orientation:	(0-1-1)				(0-1-1)				
Primary Flat Length:	22±1				22±1				mm
Secondary Flat Orientation:	(0-11)				(0-11)				
Secondary Flat Length:	12±1				12±1				mm
Carrier Concentration:	Min:	3E18	Max:	8E18	Min:	3.15E18	Max:	7.70E18	cm ⁻³
Resistivity:	Min:	/	Max:	/	Min:	/	Max:	/	ohm-cm
Mobility:	Min:	/	Max:	/	Min:	/	Max:	/	cm ² /V·sec
EPD:	Ave<:	300	Max<:	/	Ave<:	183	Max<:	/	cm ⁻²
Laser Mark:	Back side major flat				Back side major flat				
Edge Rounding:	0.25(Conform to SEMI Standards)				0.25(Conform to SEMI Standards)				mmR
Thickness:	Min:	600	Max:	650	Min:	600	Max:	650	µm
TTV:	Max:	15			Max:	15			µm
TIR:	Max:	15			Max:	15			µm
BOW:	Max:	15			Max:	15			µm
Warp:	Max:	15			Max:	15			µm
Surface:	Side 1:	Polished	Side 2:	Etched	Side 1:	Polished	Side 2:	Etched	
Particle Count:	/				/				
Package:	individual container filled with N ₂				individual container filled with N ₂				
Epi-ready:	Yes				Yes				
Quantity:	50								pcs
Area:	/								Inch ²
Wafer Number:	see Annex 1								
Quality Guarantee Period:	6 months								
Storage Suggestion:	Keep in dark place with moisture-proof								

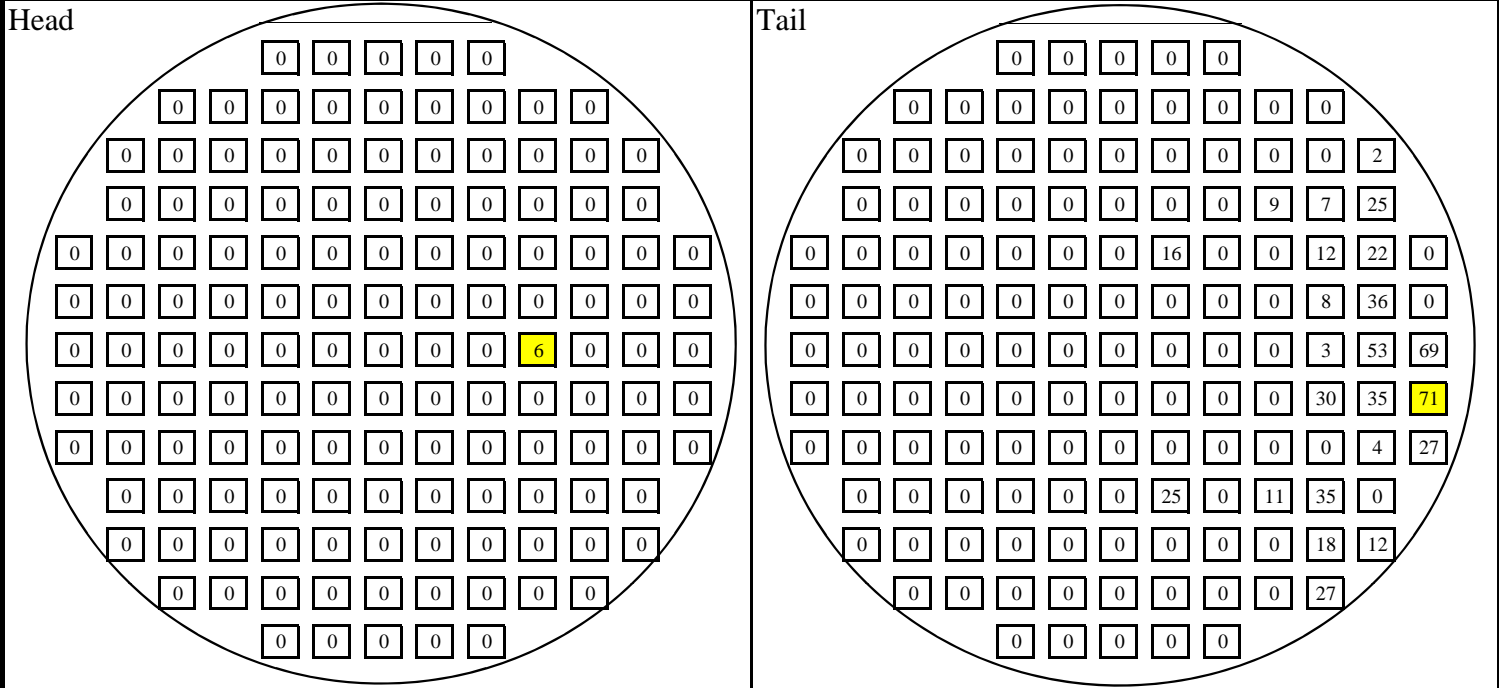
Inspector/Date: 3th Aug,2021	Approved/Dtae: 5th Aug, 2021
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Dislocation density(EPD) Inspection Report

Sample Information

P.O.No.	210707	Diameter(inch)	3
Dopant	S	Microscopic magnification	10×20

Result



Test Method		Item	Head	Tail
Diameter(mm)	1.68	Max Count	6	71
Coefficient(cm ⁻²)	45	Max EPD(cm ⁻²)	270	3195
<p style="font-size: 1.2em; color: blue;">137 Points</p>		Ave Count	0.04	4.07
		Ave EPD(cm ⁻²)	2	183
		Standard(cm ⁻²)	<300	
		Judgement		
		Inspector/Date:		